What is claimed is:

1. A III-V compound semiconductor having a layer formed from a first III-V compound semiconductor expressed by the general formula ${\rm In}_u{\rm Ga}_v{\rm Al}_w{\rm N}$ (where $0\!\leq\!u\!\leq\!1$, $0\!\leq\!v\!\leq\!1$, $0\!\leq\!w\!\leq\!1$, u+v+w=1), a pattern formed on said layer from a material different not only from said first III-V compound semiconductor but also from a second III-V compound semiconductor hereinafter described, and a layer formed on said first III-V compound semiconductor and said pattern from said second III-V compound semiconductor expressed by the general formula ${\rm In}_x{\rm Ga}_y{\rm Al}_z{\rm N}$ (where $0\!\leq\!x\!\leq\!1$, $0\!\leq\!y\!\leq\!1$, $0\!\leq\!z\!\leq\!1$, x+y+z=1), wherein the full width at half maximum of the (0004) reflection X-ray rocking curve of said second III-V compound semiconductor is 700 seconds or less regardless of the direction of X-ray incidence.

2. A III-V compound semiconductor having a layer formed from a first III-V compound semiconductor expressed by the general formula ${\rm In_uGa_vAl_wN}$ (where $0 {\le} {\rm u} {\le} 1$, $0 {\le} {\rm v} {\le} 1$, $0 {\le} {\rm w} {\le} 1$, ${\rm u} + {\rm v} + {\rm w} = 1$), a pattern formed on said layer from a material different not only from said first III-V compound semiconductor but also from a second III-V compound semiconductor hereinafter described, and a layer formed on said first III-V compound semiconductor and said pattern from said second III-V compound semiconductor expressed by the general formula ${\rm In_xGa_vAl_zN}$ (where $0 {\le} {\rm x} {\le} 1$, $0 {\le} {\rm y} {\le} 1$, $0 {\le} {\rm z} {\le} 1$,

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x + y + z = 1), where in an upper surface of said pattern is not in contact with said second III-V compound semiconductor.

- 3. A III-V compound semiconductor as set fourth in claim 1 or 2, wherein said pattern is formed from W.
- 4. A III-V compound semiconductor as set fourth in claim 1 or 2, wherein the first III-V compound semiconductor is expressed by the general formula $In_uGa_vAl_wN$ (where $0 \le u \le 1$, $0 \le v \le 1$, $0.01 \le w \le 1$, u + v + w = 1).
- 5. A III-V compound semiconductor as set fourth in claim 1 or 2, wherein said pattern is a lamination comprising at least two layers which are contacting each other and made of different materials.
- 6. A III-V compound semiconductor as set fourth in claim 5, wherein said pattern is a lamination comprising at least a layer made of W and a layer made of a material other than W.
- 7. A III-V compound semiconductor as set fourth in claim 5, wherein said pattern is a lamination comprising at least a layer made of W and a layer made of SiO_2 .
- 8. An electronic device comprising the III-V compound semiconductor as set fourth in claim 1 or 2.
- 9. A light emitting device comprising the III-V compound semiconductor as set fourth in claim 1 or 2.

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